Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/758,549	OKADA, HIDEHIKO
Examiner	Art Unit
Le Nguyen	2174

	SEAR	CHED	
Class	Subclass	Date	Examiner
715	705	9/8/2005	LVN
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
US-PAT		9/8/2005	LVN